

DEVICE FOR TESTING ELECTRONIC COMPONENTS

ABSTRACT

The invention proceeds from a device for testing electronic components, comprising at least one test base (13) for contacting the electronic components (17) and comprising a test head, which is coupled electrically to the test base (13). In accordance with the invention, in order to forward signals between the test base (13) and test head, an adapter board (1) is provided, which, on its side facing the test base (13), has contact areas (2) which are adapted to the position of contacts of the test base (13), and, on its side facing away from the test base (13), is provided with contact sockets (4) which are adapted to the position of contact pins (10) of the test head or an intermediate board (6), the contact areas (2) each being electrically conductively connected to corresponding contact sockets (4).

(Fig. 2)